



Dose Scenarios for PXD/DEPFET

**13th International Workshop on DEPFET Detectors and
Applications**

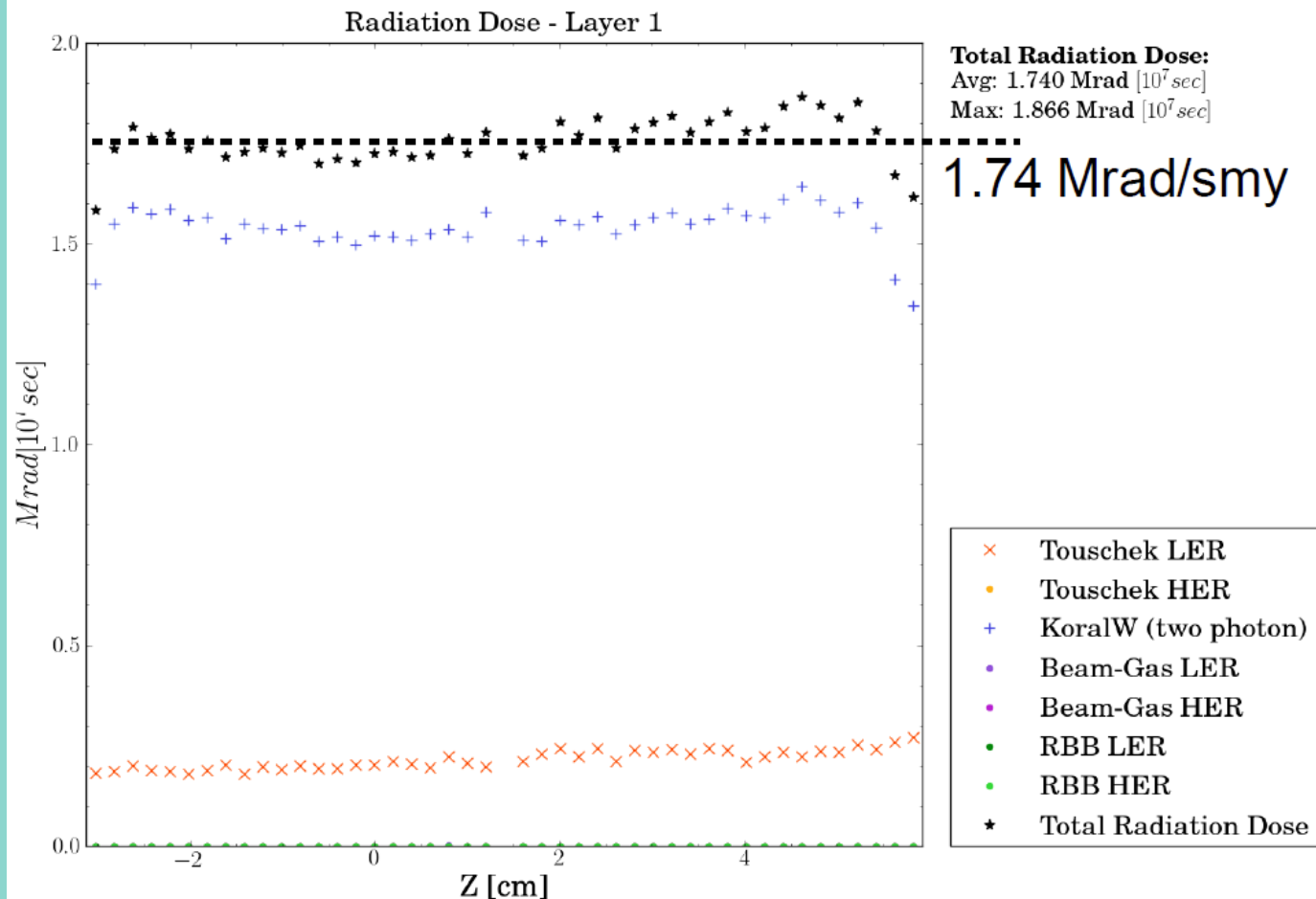
Ringberg, 13.6.2013

Andreas Ritter





Inhomogeneous Irradiation along z 1/2



1. Inhomogeneous dose along z is inevitable.
2. Besides the 3-fold segmentation, all DEPFETs get the same gate voltage
3. Difference in various Pixels increase with increasing dose (== operation years)
4. → Some scenarios can be thought of.

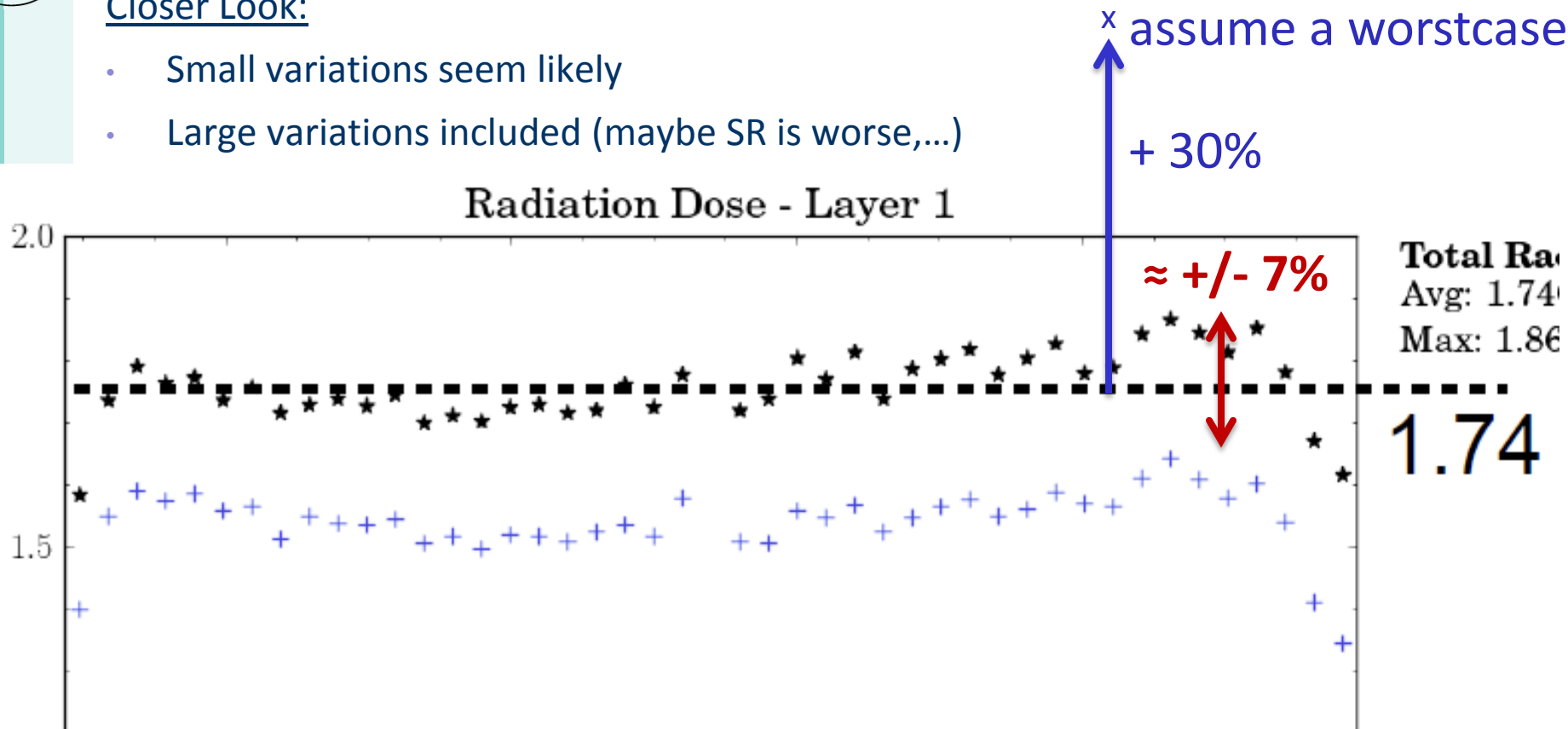
[Total Radiation Dose (Layer 1, w/o SR) background, taken from
A. Moll, Talk at B2GM Bad Aibling 2012, PXD Background]



Inhomogeneous Irradiation along z 2/2

Closer Look:

- Small variations seem likely
- Large variations included (maybe SR is worse,...)

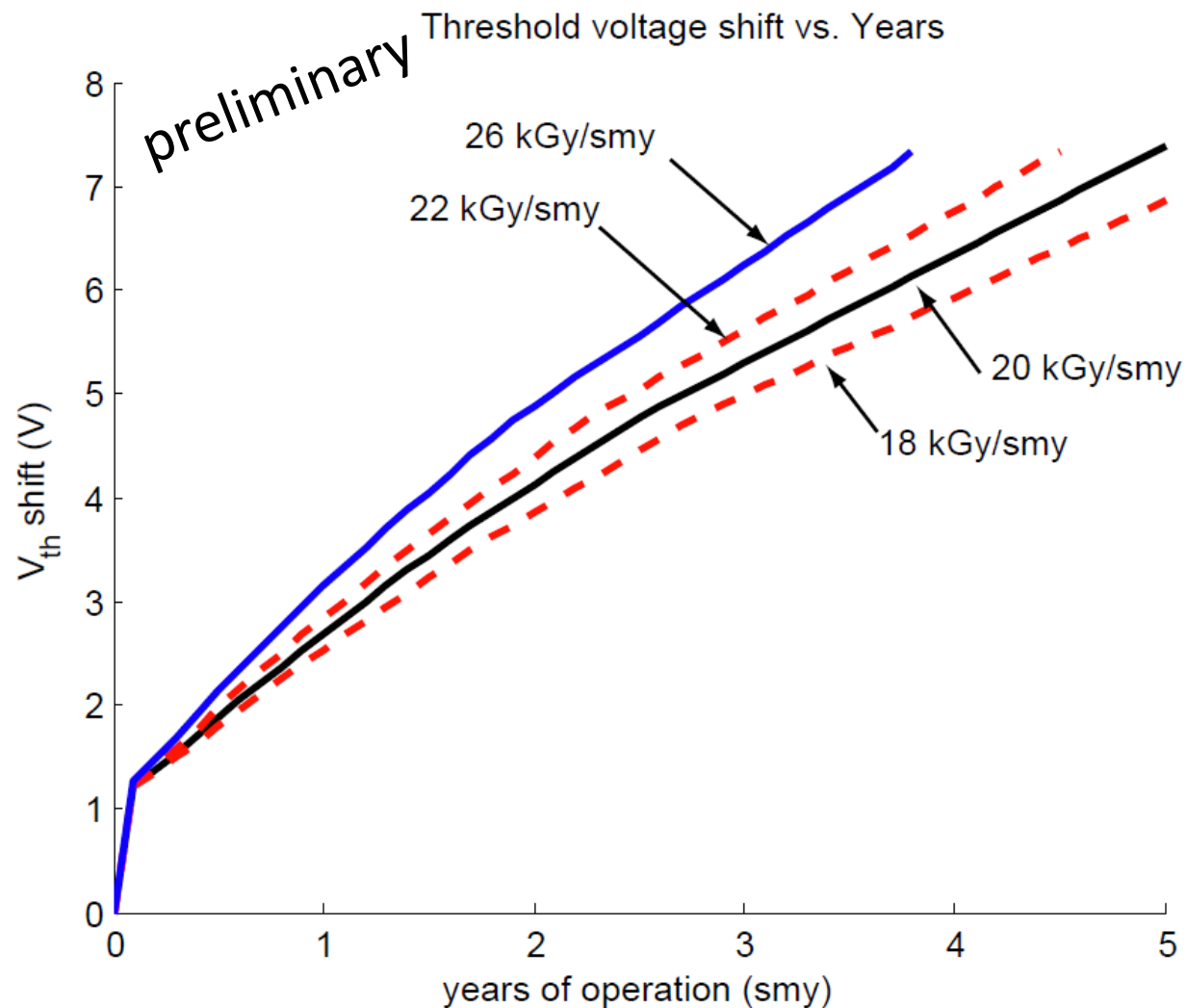


Assume for Scenarios:

- Average 20 kGy/smy
- Variations of 2 kGy/smy ($\pm 10\%$)
- Highly irradiated DEPFET with 26 kGy/smy



Diff. Dose leads to diff. V_{th}

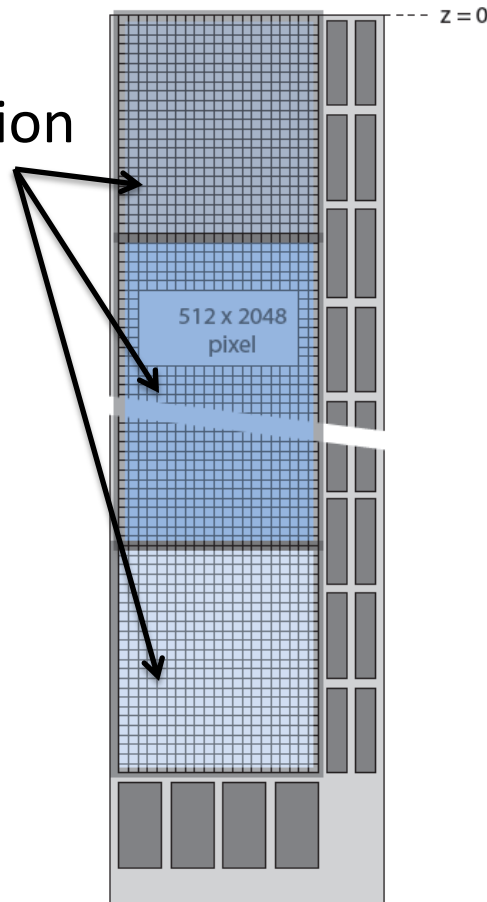


1. Baseline current is referred to the pixel with the highest dose
2. Other DEPFETs have then a too high voltage at the gate, which leads too a higher drain current.
3. + g_m degradation



3-fold segmentation of half-ladder - Remedy

3-fold
Segmentation
(*sketch*)



1. „Global“ Shifts in V_{Gate} and $V_{\text{ClearGate}}$ can be adapted by adjusting voltages according to the shift.
2. Inhomogeneous Shifts V_{Gate} and $V_{\text{ClearGate}}$ can be partially compensated due to 3-fold segmentation of half ladder.
3. However, which current differences arises when inhomogeneity is within one patch?
→ This Talk gives an overview of a work in progress (there is room for improvement...)



Scenarios

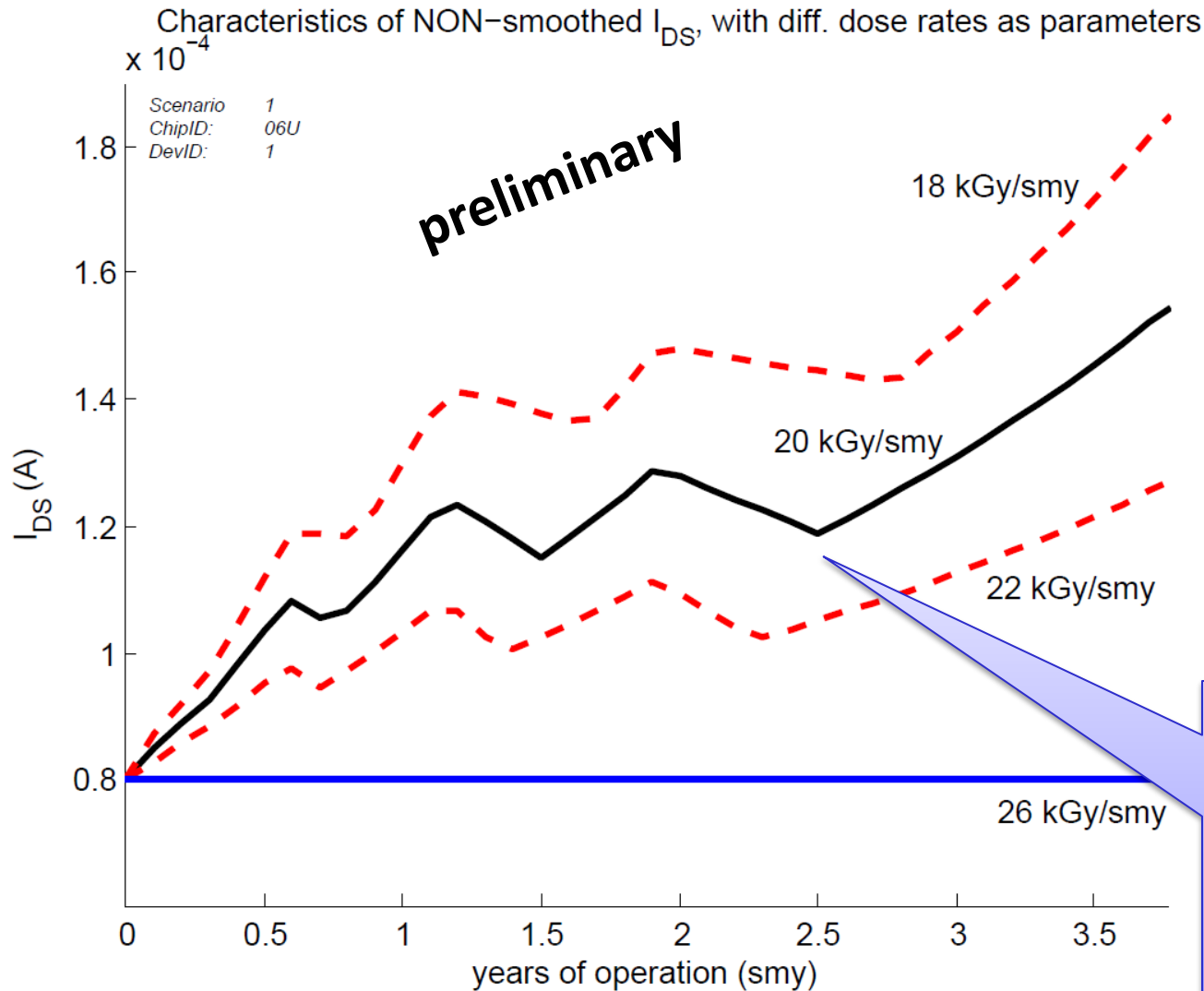
Scenario	Avg. Dose rate	Dose rate variation	I_{DS} baseline current
Scen. 1, Max	20 kGy/smy	6 kGy/smy	80 μ A
Scen. 2, Medium	20 kGy/smy	+/- 2 kGy/smy	80 μ A
Scen. 3, Max + low I_{DS}	20 kGy/smy	6 kGy/smy	50 μ A
Scen. 4, Medium+low I_{DS}	20 kGy/smy	+/- 2 kGy/smy	50 μ A

Are these scenarios realistic?

-30 % difference (Max-Scenarios) in irradiation is certainly harsh → Curiosity



Scenario 1, Max

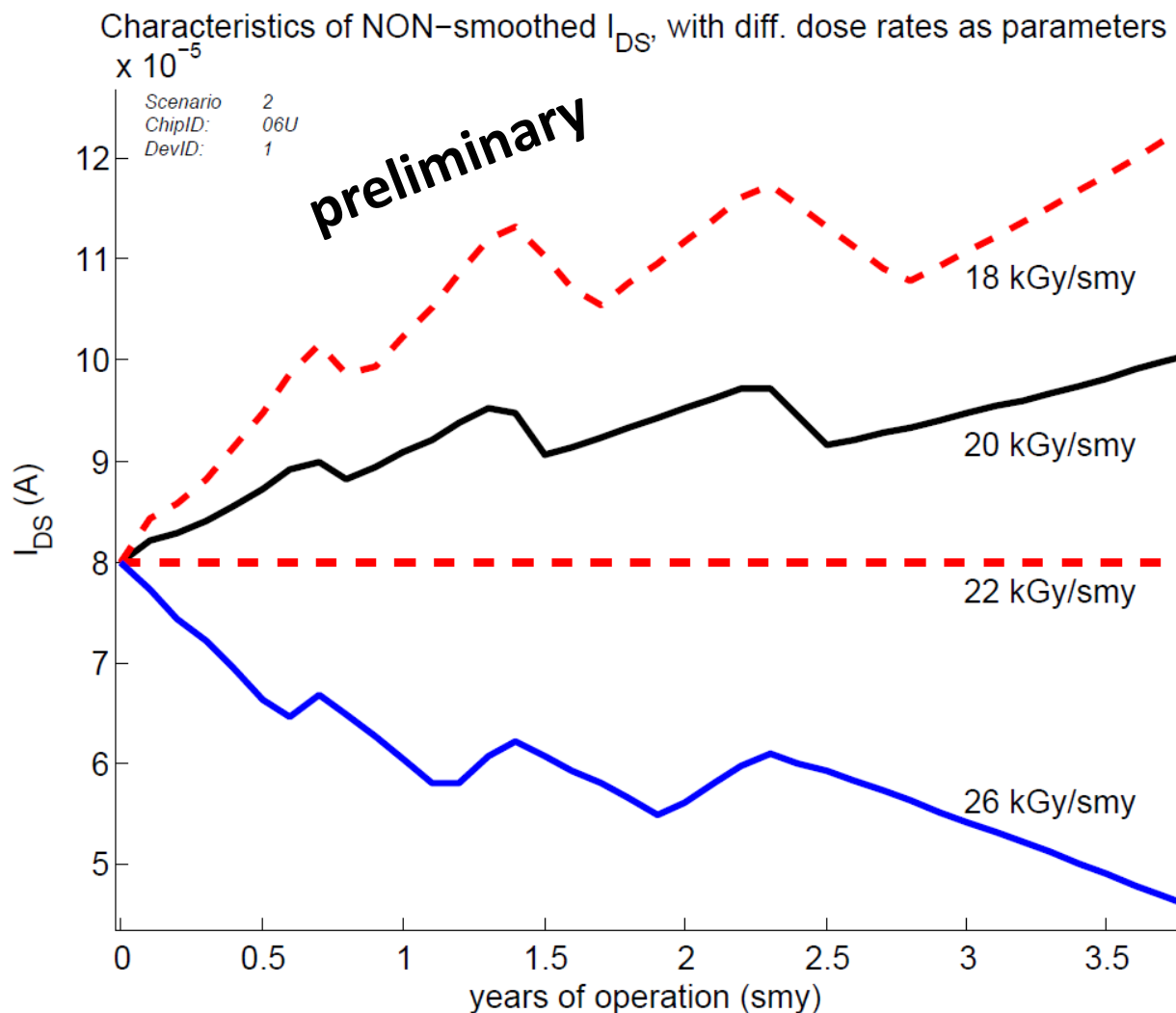


1. Baseline current is set to 80 μ A for the highest irradi. Pixel (26 kGy/smy).
2. Harsh Scenario, leads to big differences in I_{DS} .

Dips arise from analyse method (generation of $I_{DS}(V_{GS})$ curves)



Scenario 2, Medium

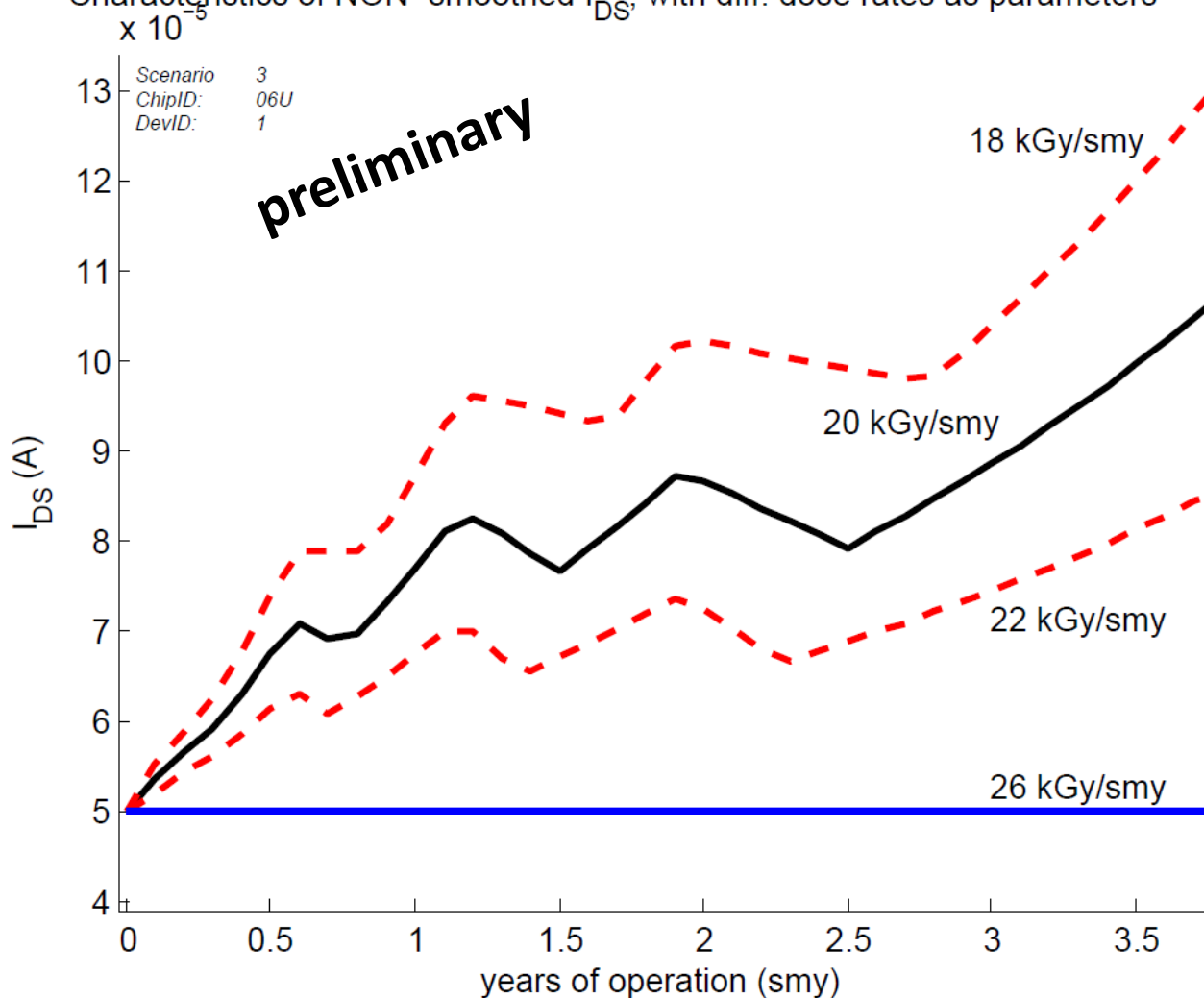


1. Baseline current is set to $80 \mu\text{A}$ for a medium irradi. Pixel (22 kGy/smy).
2. Differences in I_{DS} is still large, but if highest Irradiation happens only to few pixels it might be OK.



Scenario 3, Max + 50 μ A

Characteristics of NON-smoothed I_{DS} , with diff. dose rates as parameters

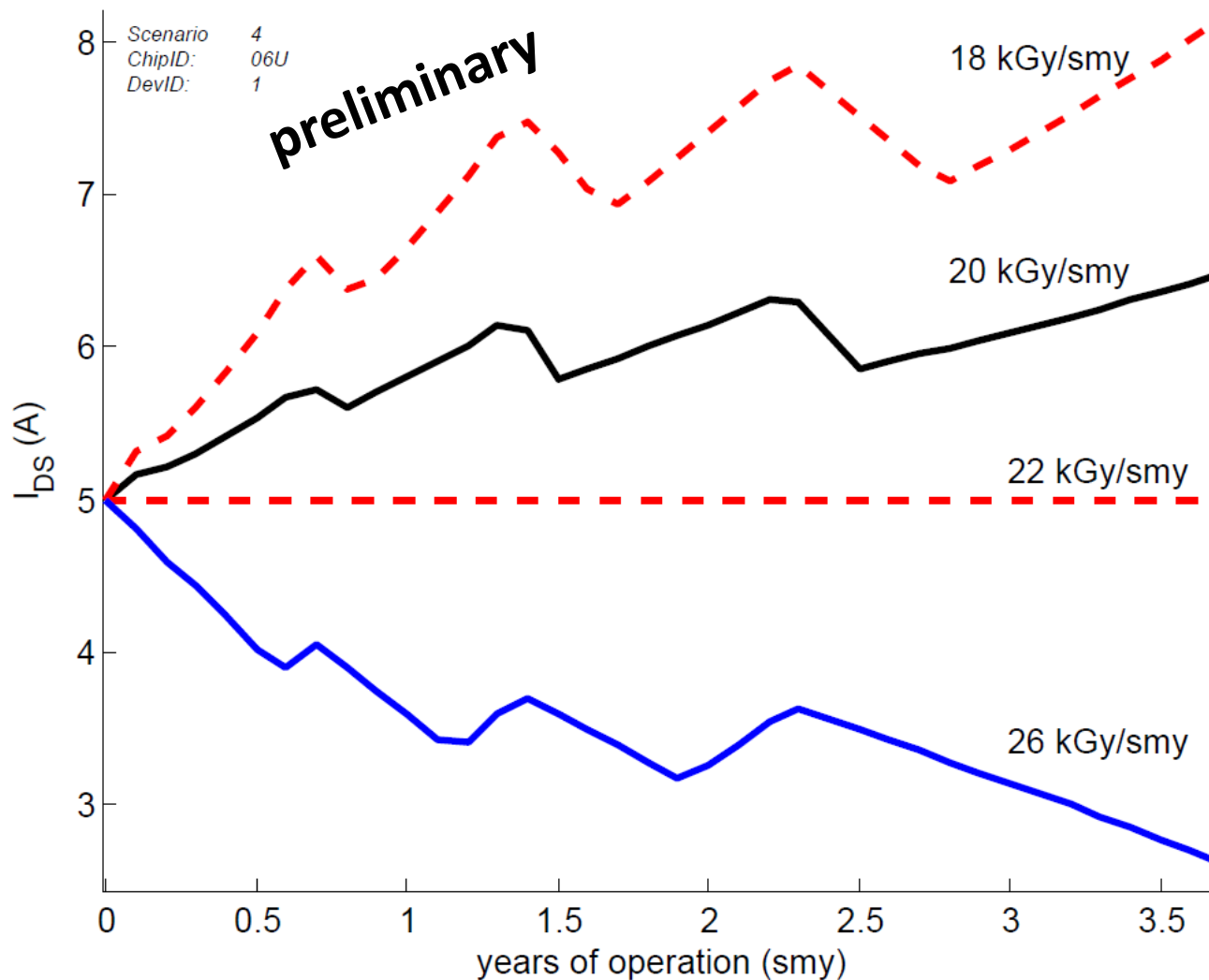


1. Baseline current is set to 50 μ A for the highest irradi. Pixel (26 kGy/smy).
2. Also not a good Scenario, leads to differences in I_{DS} (yet better as in Scenario 1).



Scenario 4, Medium+ 50 μ A

Characteristics of NON-smoothed I_{DS} , with diff. dose rates as parameters
 $\times 10^{-5}$



1. Baseline current is set to 50 μ A for the medium irradi. Pixel (22 kGy/smy).
2. *Good Scenario.* Difference in I_{DS} is small + when neglecting highly irradi. Pixels
→ even better.



Summary & Outlook for non-smoothed data

Scenario	I_{DS} diff. at 3.5 years (all)	I_{DS} diff. at 3.5 years (neglecting high irradi.)
Scen. 1, Max	100 μA	-
Scen. 2, Medium	70 μA	40 μA
Scen. 3, Max + low I_{DS}	80 μA	-
Scen. 4, Medium+low I_{DS}	50 μA	30 μA

Summary and Outlook:

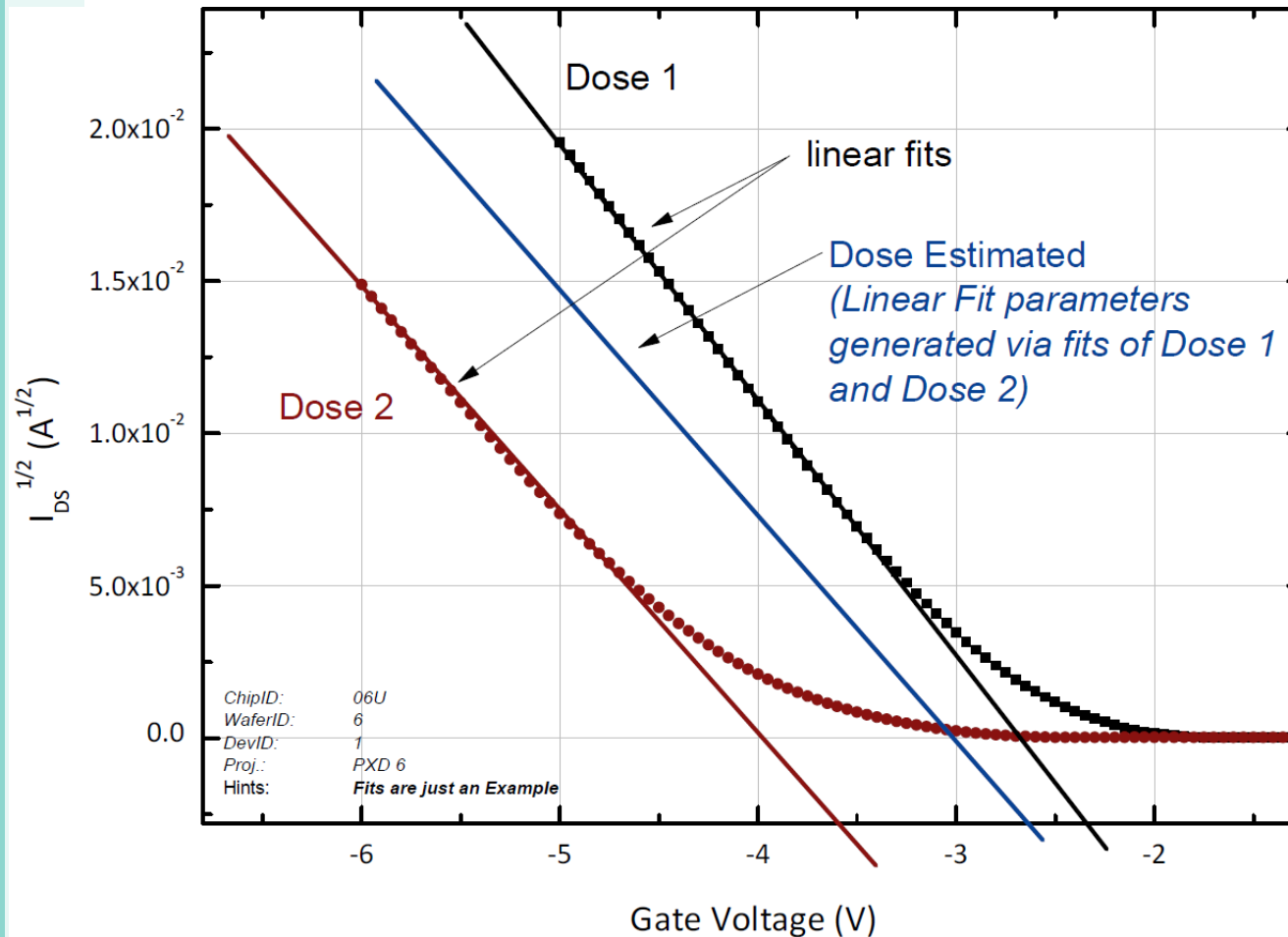
- Analyse method is under discussion/improvement
- If running at lower I_{DS} is possible, it would reduce the amount of I_{DS} difference.
- If neglecting of highly irradiated pixels (or if they don't arise at all → *Dose(z) from the beginning predicts $\approx 7\%$ difference*) could improve the situation. Max scenarios not realistic.
- Does Synchrotron radiation worsen the situation?
- What is possible with the read-out electronic?
- What effect do these scenarios have on the Clear Gates?



Backup



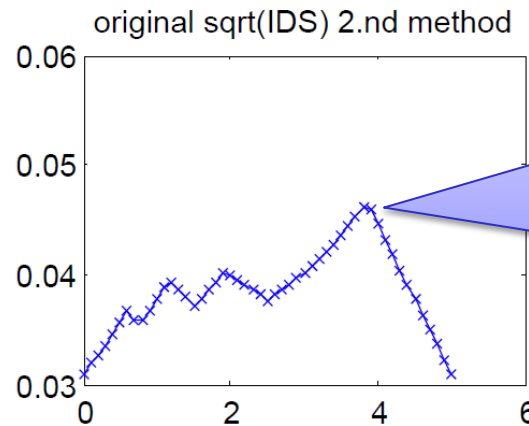
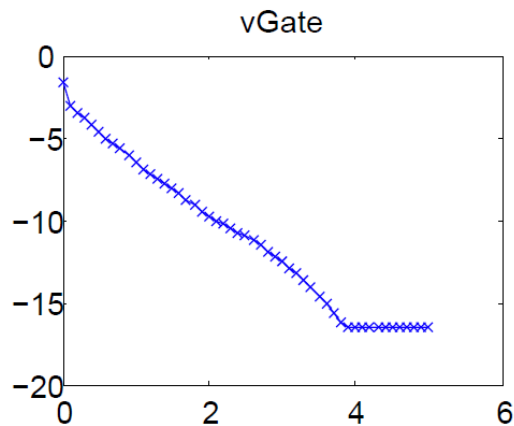
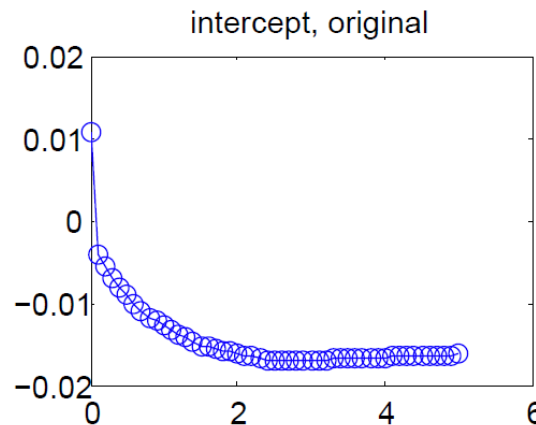
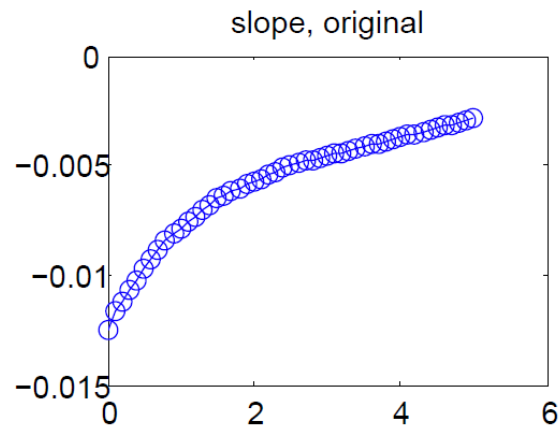
Analysis Approach 1/4



Generate linear fit
params at desired
dose (sqrt
Parameters)



Analysis Approach 2/4

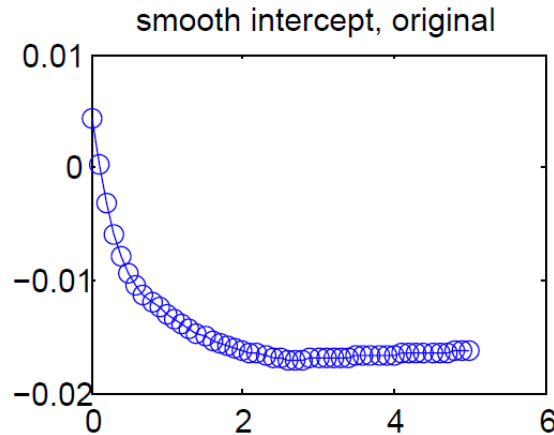
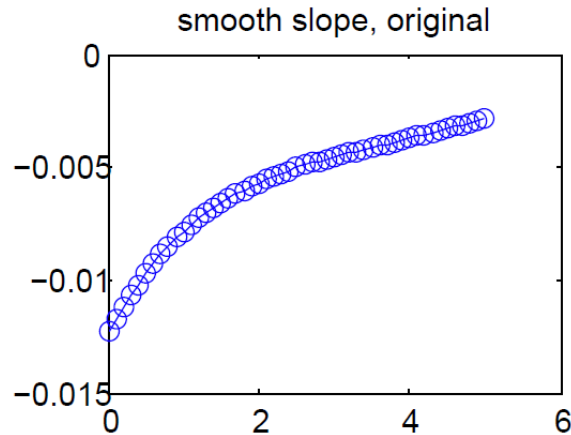


Sqrt linear fit params
and vGate (set by
highest irradiated
DEPFET) set I_DS

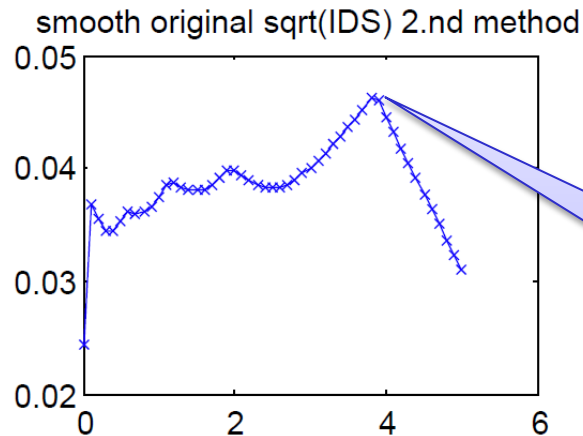
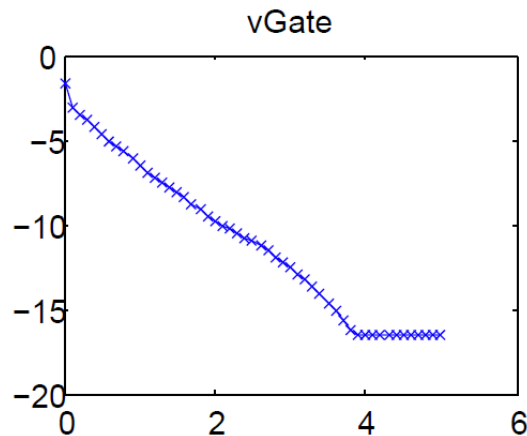
vGate = const,
slope decrease
further...



Analysis Approach 3/4



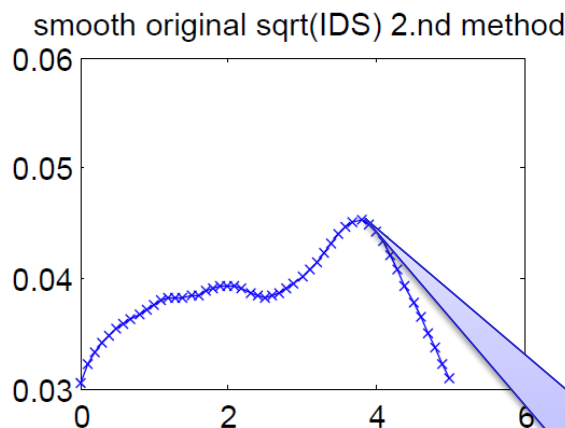
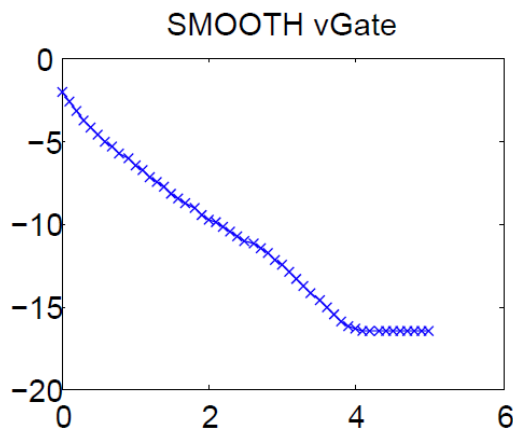
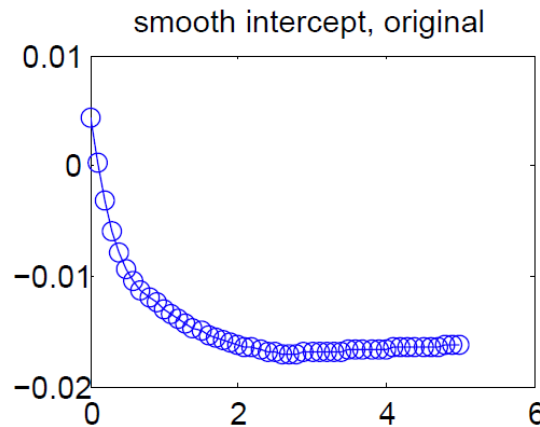
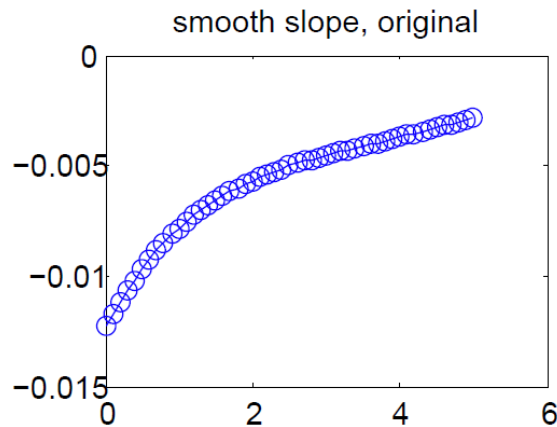
To avoid bumps in slope and intercept a soft smoothing was applied to them. Still bumps and kinks in $\sqrt{I_{DS}}$ due to bumps in v_{Gate} .



$v_{Gate} = \text{const}$,
slope decrease
further...



Analysis Approach 4/4



In addition to smoothing of slope and intercept, also vGate was smoothed. This changed also a bit the baselinecurrent. I_DS was again set to baseline an the other DEPFETs were shifted accordingly

vGate = const,
slope decrease
further...